

Form PTO-1449 U.S. Department of Commerce
Patent & Trademark Office

Atty. Docket No.
2022/48640

Serial No.
09/544,558

Applicants
Cyprian Uzoh et al.

Filing Date
April 6, 2000

Group Art Unit
3723

INFORMATION ENCLOSURE STATEMENT
(Use separate sheets if necessary)

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date (if appropriate)
TR	AA	3,328,273	06-1967	Creutz et al.			
	AB	4,430,173	02-1984	Boudot et al.			
	AC	4,948,474	08-1990	Miljkovic			
	AD	4,954,142	09-1990	Carr et al.			
	AE	4,975,159	12-1990	Dahms			
	AF	5,084,071	01-1992	Nenadic et al.			
	AG	5,354,490	10-1994	Ye et al.			
	AH	5,755,859	05-1998	Brusie et al.			
	AI	5,770,095	06-1998	Sasaki et al.			
	AJ	5,773,364	06-1998	Farkas et al.			
	AK	5,793,272	08-1998	Burghartz et al.			
	AL	5,807,165	09-1998	Uzoh et al.			
	AM	5,840,629	11-1998	Carpio			
	AN	5,858,813	01-1999	Scherber et al.			
	AO	5,884,990	03-1999	Burghartz et al.			
	AP	5,897,375	04-1999	Watts et al.			
	AQ	5,911,619	06-1999	Uzoh et al.			
	AR	5,922,091	07-1999	Tsai et al.			
	AS	5,930,669	07-1999	Uzoh			
	AT	5,933,753	08-1999	Simon et al.			
	AU	5,954,997	09-1999	Kaufman et al.			
	AV	6,004,880	12-1999	Liu et al.			
	AW	6,063,506	05-2000	Andricacos et al.			
TR	AX	6,066,030	05-2000	Uzoh			

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		Document	Date	Country	Class	Sub-class	Translation Yes No
TR	AY	98/27585	06-1998	PCT			

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

TR	AZ	James J. Kelly et al., "Leveling and Microstructural Effects of Additives for Copper Electrodeposition", Journal of the Electrochemical Society, 146 (7), 1999, Pages 2540-2545.					
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Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date (if appropriate)
TR	AA	5,256,565	10-1993	Bernhardt et al.			
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	AC						
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FOREIGN PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

		Document	Date	Country	Class	Sub-class	Translation Yes No
	AW						
	AX						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<div style="font-size: 2em; font-family: cursive;">TK</div>	AY	Joseph M. Steigerwald et al., "Chemical Mechanical Planarization of Microelectronic Materials", A Wiley-Interscience Publication, 1997 by John Wiley & Sons, Inc. pages 212-222.
	AZ	

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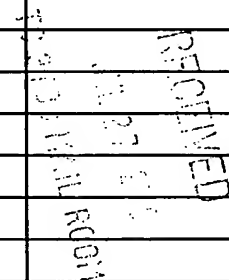
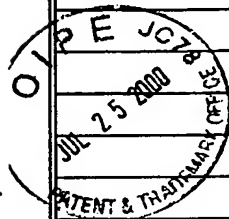
Timothy V. Eley

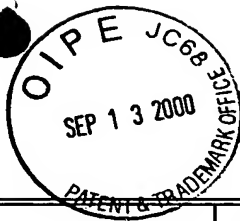
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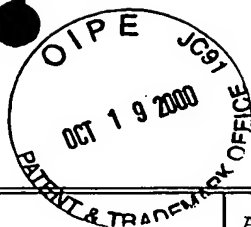
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				Filing Date April 6, 2000		Group 3723	
U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date (if appropriate)
<i>UR</i>	AA	6,071,388	06-2000	Uzoh	 		
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EXAMINER <i>Timothy R. Eley</i>				DATE CONSIDERED <i>08/23/01</i>			
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FOREIGN PATENT DOCUMENTS

		Document	Date	Country	Class	Sub-class	Translation Yes No
	AK						
	AL						
	AM						
	AN						
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>TR</i>	AQ	Wei William Lee et al., "Low-Dielectric-Constant Materials for ULSI Interlayer Dielectric Applications", MRS Bulletin, October 1997, pages 19-23.
<i>TR</i>	AR	Changming Jin et al., "Nanoporous Silica as an Ultralow-k Dielectric", "MRS Bulletin, October 1997, pages 39-42.
<i>TR</i>	AS	Ken Monnig, "Why Copper and Low K?", Future Fab, Issue 5, May 3, 1999, pages 1-7.
<i>TR</i>	AT	Alexander E. Braun, "ECP Technology Faces Chemical, Dielectric Hurdles", Cahners Semiconductor International, May 2, 2000, pages 1-9.

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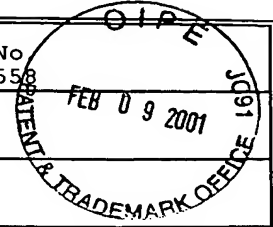
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Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date (if appropriate)
UR	AA	5,762,544	06-1998	Zuniga et al.			
	AB	5,795,215	08-1998	Guthrie et al.			
	AC	5,681,215	10-1997	Sherwood et al.			
	AD	5,516,412	05-1996	Andricacos et al.			
	AE	5,985,123	11-1999	Koon			
	AF	6,027,631	02-2000	Broadbent			
	AG	6,074,544	06-2000	Reid et al.			
	AH	6,103,085	08-2000	Woo et al.			
	AI	6,136,163	10-2000	Cheung et al.			
UR	AJ	6,176,992	01-2001	Talieh			

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UR	AK	WO 00/26443	05-2000	PCT			
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UR	AQ	Robert D. Mikkola et al., "Investigation of the Roles of the Additive Components for Second Generation Copper Electroplating Chemistries Used for Advanced Interconnect Metalization", 2000 IEEE, IEEE Electron Devices Society, Pages 117-119.
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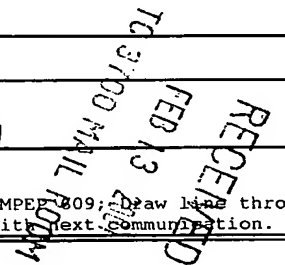
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Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date (if appropriate)
TR	AA	5,846,398	12-1998	Carpio			
	AB	5,866,031	02-1999	Carpio et al.			
	AC	6,010,964	01-2000	Glass			
	AD	6,063,306	05-2000	Kaufman et al.			
	AE	6,103,096	08-2000	Datta et al.			
	AF	6,132,586	10-2000	Adams et al.			
TR	AG	6,156,661	12-2000	Small			
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